

MOS FIELD EFFECT TRANSISTOR μ PA1709

SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

DESCRIPTION

This product is N-Channel MOS Field Effect Transistor designed for DC/DC converters and power management switch.

FEATURES

· Low on-resistance

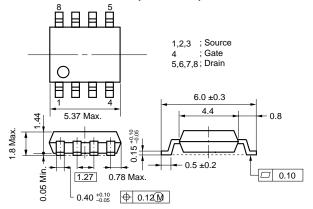
 $R_{DS(on)1} = 9.3 \ m\Omega \ (TYP.) \ (V_{GS} = 10 \ V, \ I_{D} = 4.5 \ A)$ $R_{DS(on)2} = 13.8 \ m\Omega \ (TYP.) \ (V_{GS} = 4.5 \ V, \ I_{D} = 4.5 \ A)$

- Low Ciss: Ciss = 1850 pF (TYP.)
- · Built-in G-S protection diode
- Small and surface mount package (Power SOP8)

ORDERING INFORMATION

PART NUMBER	PACKAGE
μ PA1709G	Power SOP8

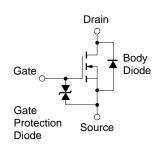
PACKAGE DRAWING (Unit: mm)



ABSOLUTE MAXIMUM RATINGS (TA = 25°C, All terminals are connected.)

Drain to Source Voltage (Vgs = 0 V)	VDSS	40	V
Gate to Source Voltage (VDS = 0 V)	Vgss	±25	V
Drain Current (DC)	I _{D(DC)}	±9.0	Α
Drain Current (pulse) Note1	D(pulse)	±36	Α
Total Power Dissipation (T _A = 25°C) Note2	PT	2.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to + 150	°C

EQUIVARENT CIRCUIT



- **Notes 1.** PW \leq 10 μ s, Duty Cycle \leq 1 %
 - 2. Mounted on ceramic substrate of 1200 mm² x 0.7 mm

Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

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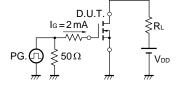
ELECTRICAL CHARACTERISTICS (T_A = 25 °C, All terminals are connected.)

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CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	RDS(on)1	Vgs = 10 V, ID = 4.5 A		9.3	12.5	mΩ
	RDS(on)2	VGS = 4.5 V, ID = 4.5 A		13.8	20.0	mΩ
Gate to Source Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	1.5	2.0	2.5	V
Forward Transfer Admittance	yfs	V _{DS} = 10 V, I _D = 4.5 A	8.0	14		S
Drain Leakage Current	Ipss	V _{DS} = 40 V, V _{GS} = 0 V			10	μΑ
Gate to Source Leakage Current	Igss	VGS = ±25 V, VDS = 0 V			±10	μΑ
Input Capacitance	Ciss	V _{DS} = 10 V		1850		pF
Output Capacitance	Coss	V _G S = 0 V		790		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		330		pF
Turn-on Delay Time	td(on)	ID = 4.5 A		27		ns
Rise Time	t r	V _{GS(on)} = 10 V		95		ns
Turn-off Delay Time	td(off)	V _{DD} = 20 V		110		ns
Fall Time	tr	$R_G = 10 \Omega$		70		ns
Total Gate Charge	Q _G	ID = 9.0 A		43.0		nC
Gate to Source Charge	Qgs	V _{DD} = 32 V		6.0		nC
Gate to Drain Charge	Q _{GD}	Vss = 10 V		14.0		nC
Body Diode Forward Voltage	V _{F(S-D)}	IF = 9.0 A, VGS = 0 V		0.78		V
Reverse Recovery Time	trr	IF = 9.0 A, VGS = 0 V		47		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/ μ s		44		nC

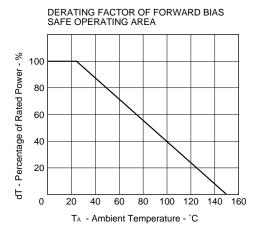
TEST CIRCUIT 1 SWITCHING TIME

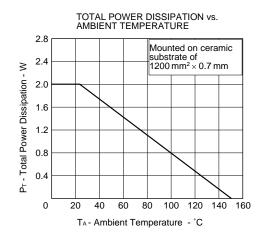
$PG. \square R_G = 10 \, \Omega$ $V_{GS} = 10 \, \Omega$ $V_{GS} = 10 \, \Omega$ $V_{Wave Form} = 10 \, \Omega$

TEST CIRCUIT 2 GATE CHARGE

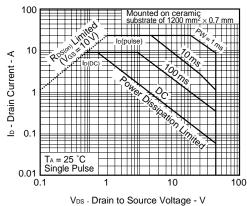


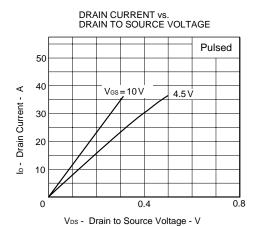
TYPICAL CHARACTERISTICS (TA = 25 °C)



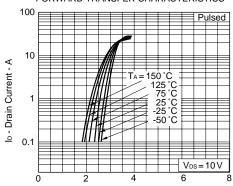


★ FORWARD BIAS SAFE OPERATING AREA



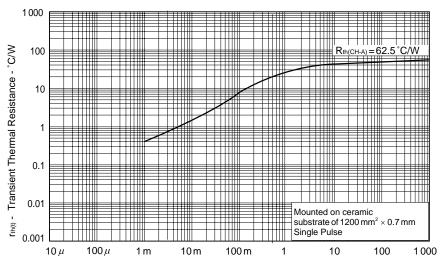


FORWARD TRANSFER CHARACTERISTICS

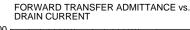


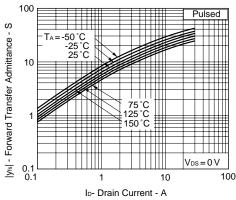
Vss - Gate to Source Voltage - V

TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

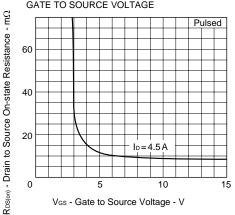


PW - Pulse Width - s

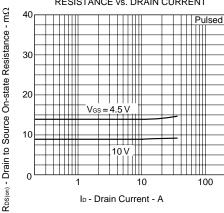




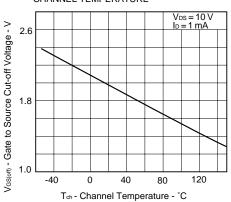
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



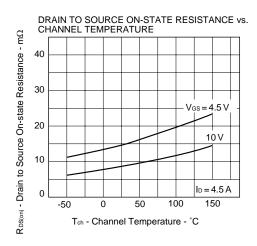
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT

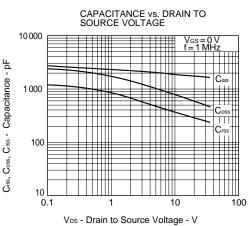


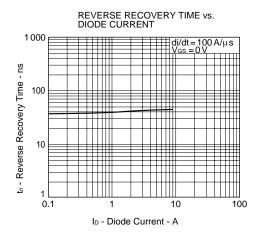
GATE TO SOURCE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE

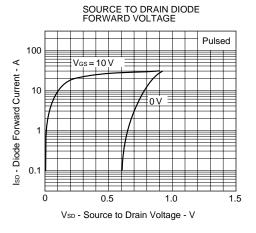


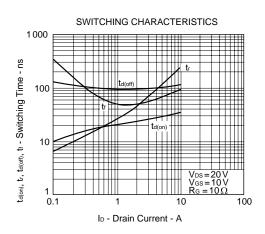
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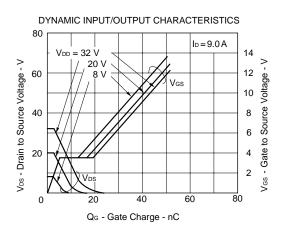












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NEC μ PA1709

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